

# Image simulation in high resolution transmission electron microscopy considering atom as an electrostatic interferometer



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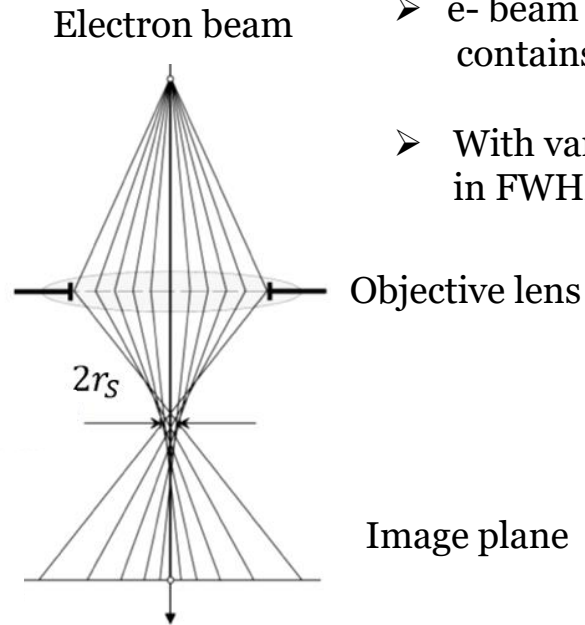
JNCASR

# Introduction to image simulation

## Aberration corrected FEI TITAN<sup>3</sup>™ 80-300 kV



## Image formation in TEM



- e- beam passing through the sample contains all the information
- With varying defocus ( $\Delta f$ ), changes in FWHM is expected

## Simulated HRTEM images

MoS<sub>2</sub>

BN

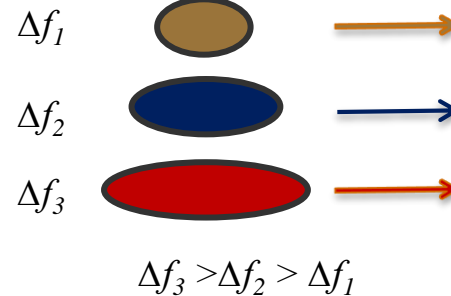
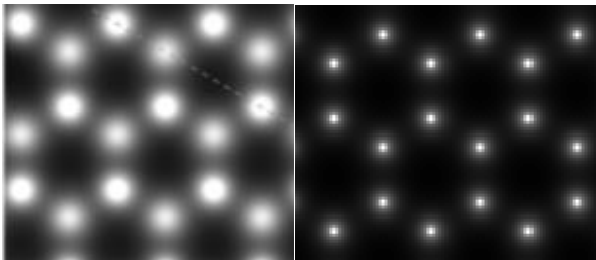
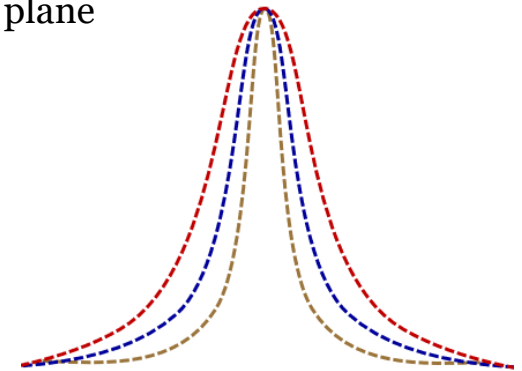


Image plane



# Existing methods of image simulation

## 1. Zernike phase object and WPOA

Zernike phase object  $F(x) = e^{i\phi(x)}$  or  $\sim 1 + i\phi(x)$

WPOA image intensity  $I(x, y) = \{1 + 2\phi(x)\}$

$$I(x, y) = 1 + 2\sigma\phi_p(-x, y) * \mathcal{F}\{\sin\chi(u, v)P(u, v)\}$$

- Pure phase/weak scattering object
- Intensity has linear dependency on the phase
- Without the WPOA, no information available at the image plane

## 2. Atomic scattering factor

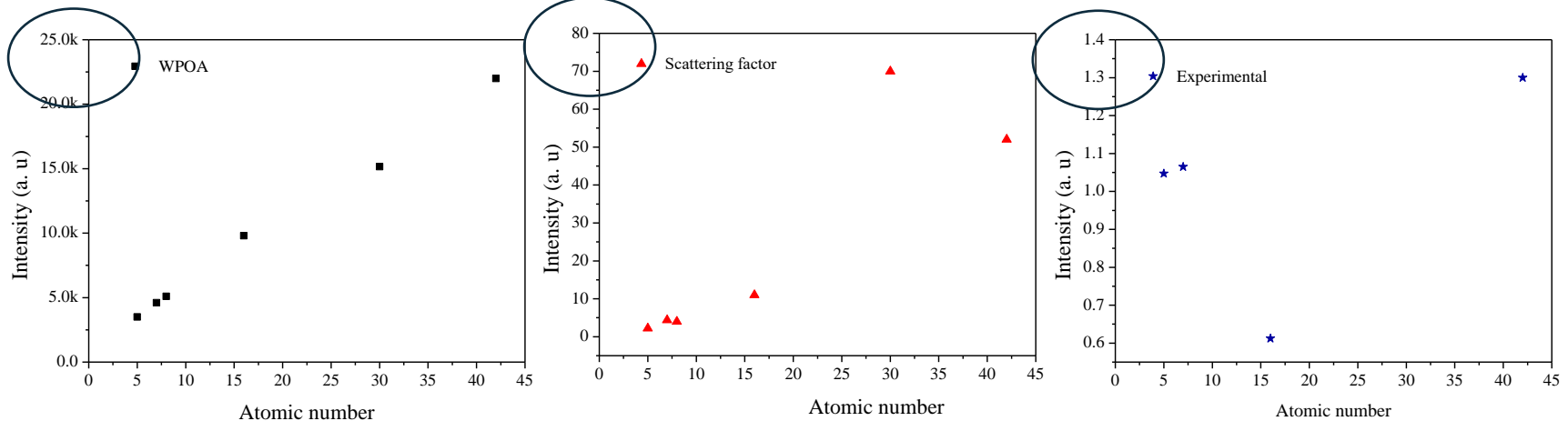
Moliere scattering factor

$$f_e(k) = \frac{2\pi i}{\lambda} \int_0^{\infty} J_0(2\pi kr) \{1 - \exp[i\sigma \int V(x, y, z) dz]\} r dr$$

$$\text{Intensity } g(x) = \left| 1 + 2\pi i \int_0^{k_{max}} f_e(k) \exp[-i\chi(k)] J_0(2\pi kr) k dk \right|^2$$

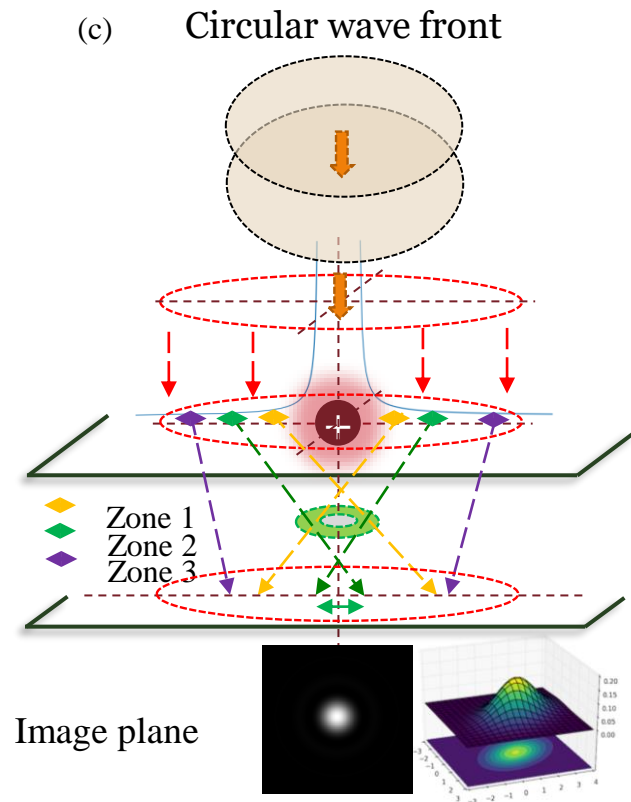
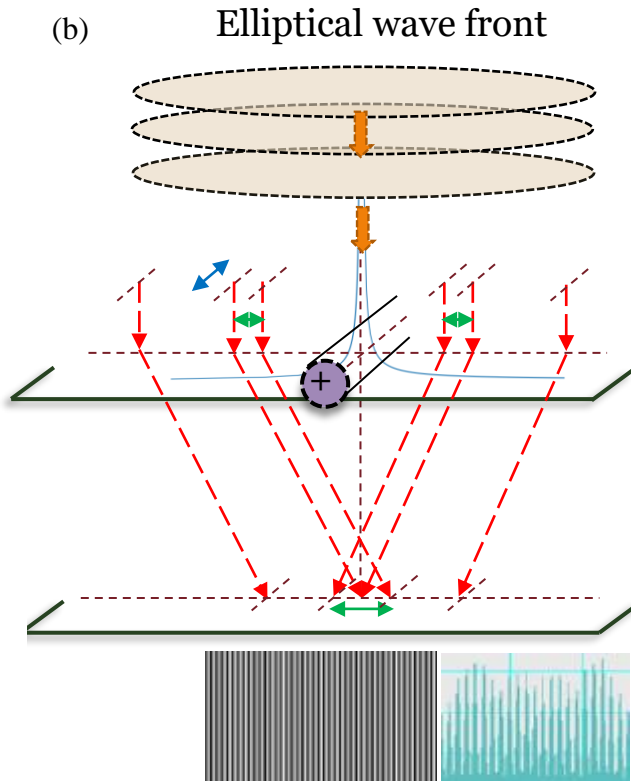
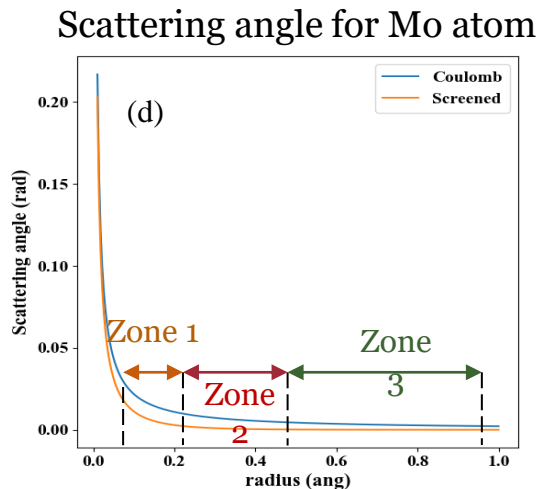
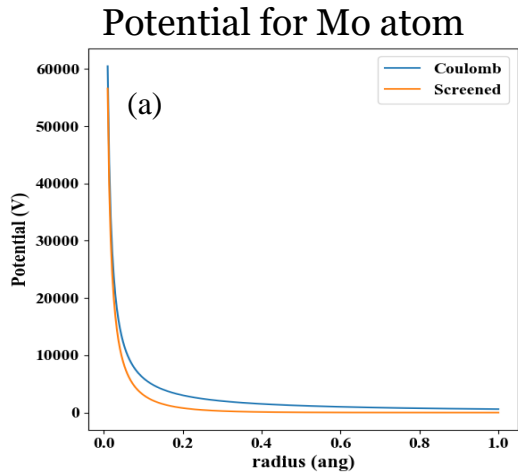
- Moliere scattering factor is considered
- Intensity values are calculated for

### Theory v/s experiment



- WPOA intensity varies linearly and it is very high
- Scattering factor based intensity is not linear and it is still high
- Experimental data shows change in intensity is non-linear

# Introducing a new method : Atom as an electrostatic interferometer

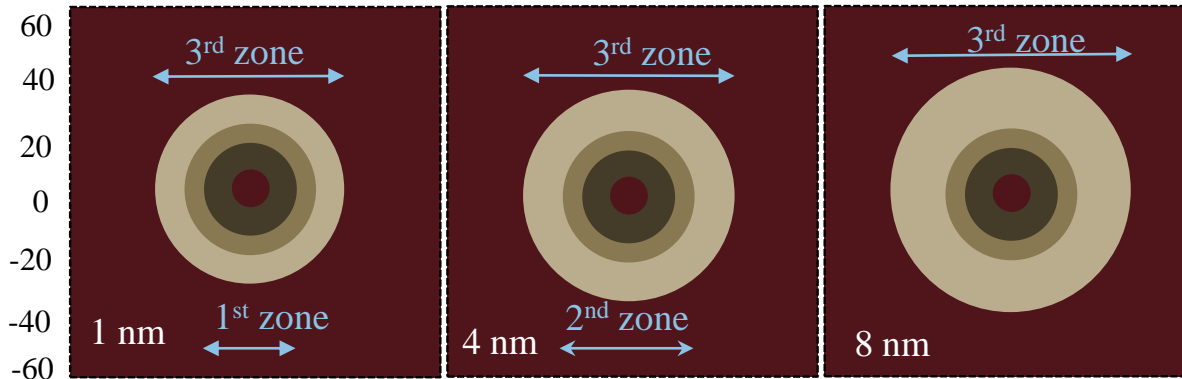


$$I_{rad int}(r) = a_1^2 + a_2^2 + 2a_1a_2 \cos(2\pi q_c r) * 2\pi(r_{max} - r)$$

- Off-axis e- holography : Elliptical wave front and interference due to single pair of scattering wave vectors
- New method : Circular wave front and interference due to a range of scattering wave vectors
- Zones are based on the same range of scattering angles & intensity from different zones scaled as  $2\pi r$
- Modified intensity equation with the flux balance calculates the image pattern

# Results and discussion

## Different zones and corresponding intensity pattern



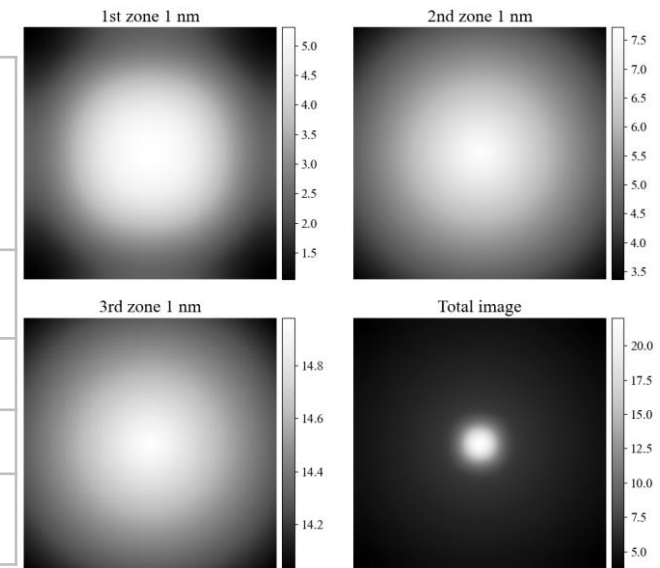
- Zones with varying defocus ( $\Delta f$ ) of 1, 4 and 8 nm
- Width of 3<sup>rd</sup> zone is increasing as  $\Delta f$  increases
- Image of an atom calculated as a sum of all zones

Mo (Z=42)

Radial distance (pm) & zones	Rim width h (pm)	Mean scattering angle (rad)	Length on optic axis (nm)	Intensity (with flux balance)
1-1.77	0.77	0.1092	1	6.82
1.77-8.37	6.6	0.0275	1	7.61
8.76-9.54	0.78	0.0092	1	13.73
8.76-15.36	6.60	0.0067	4	9.93
8.76-18.85	10.09	0.0061	8	11.03

B (Z=5)

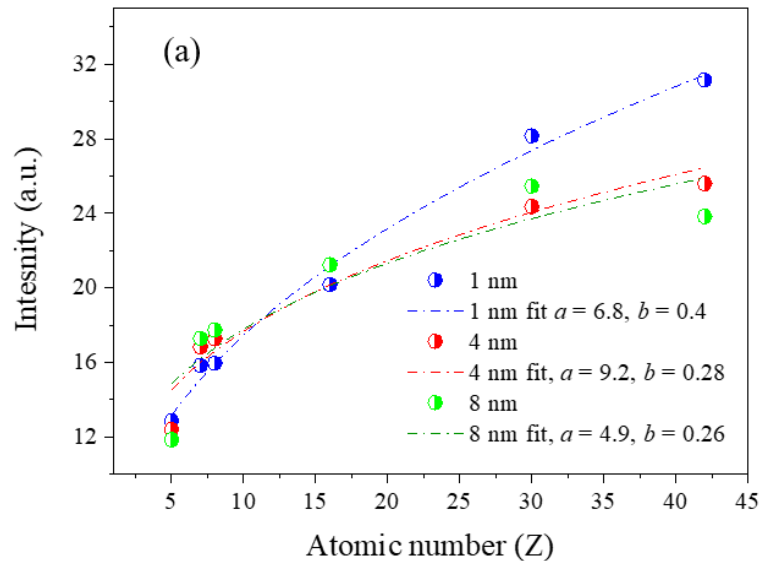
Radial distance (pm) & zones	Rim width h (pm)	Mean scattering angle (rad)	Length on optic axis (nm)	Intensity (with flux balance)
1-2.16	1.55	0.014	1	5.09
2.16-4.49	1.64	0.0069	1	7.77
2.16-7.99	6.21	0.0052	4	7.31
2.16-10.31	8.93	0.0049	8	6.76



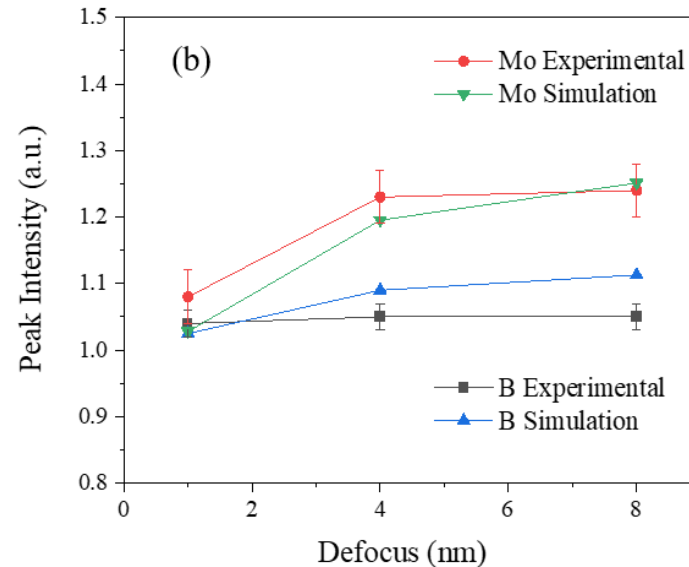
# Results and discussion

## Comparison of the experimental results with the new method of image simulation

Without aberration



With aberration



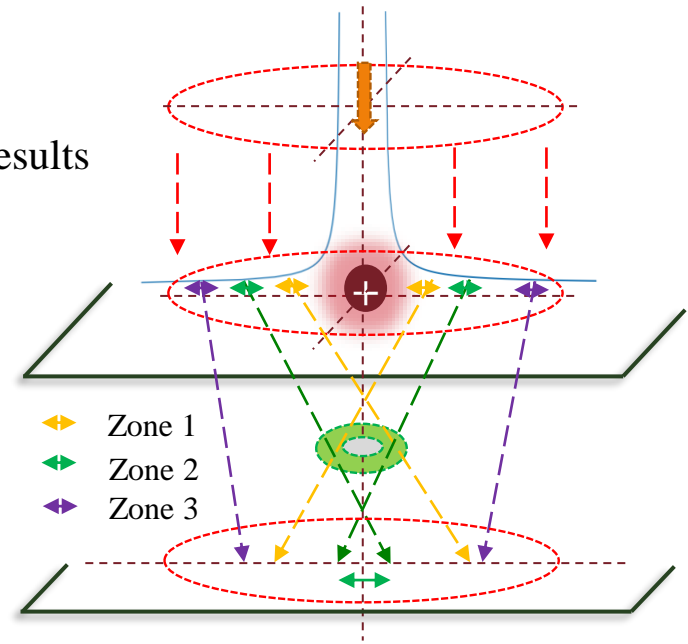
- Peak intensity falls significantly compared to the ideal lens case after considering the aberration
- Simulated result with aberration is in good agreement with the experimental data
- Intensity calculated is proportional to  $Z^{0.3 \sim 0.4}$

$$I = a Z^b \quad b \approx 0.3-0.4$$

# Summary

- ❖ New method of image simulation is introduced in HRTEM considering atom as an electrostatic interferometer and the results match well with the experimental values.
- ❖ Intensity is proportional to  $Z^{0.4}$ .

$$I_{rad\ int}(r) = a_1^2 + a_2^2 + 2a_1a_2 \cos(2\pi q_c r) * 2\pi(r_{max} - r)$$



# Acknowledgments

- ❖ I sincerely thank my research supervisor [Prof. Ranjan Datta](#) for his constant support, guidance and encouragement.
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